CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Accredited Labs dba Holts Precision (S.W.CT)
400 Chapel Road, Unit 3A
South Windsor, CT 06074
(and satellite locations as shown on the scope)

Fulfills the requirements of

ISO/IEC 17025:2017

In the field(s) of

CALIBRATION and **DIMENSIONAL MEASUREMENT**

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 15 June 2028

Certificate Number: AC-3489

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Aldinger Company, dba Holts Precision (S.W.CT)

400 Chapel Road, Unit 3A
South Windsor, CT 06074
Matthew Shaw 423-617-9006

Services performed at satellite locations as indicated in far-right column:

W.B.MA	**W.S.MA**
793 West Center Street	171 Doty Circle
West Bridgewater, MA 02379	West Springfield, MA 01089

CALIBRATION AND DIMENSIONAL MEASUREMENT

ISO/IEC 17025 Accreditation Granted: **15 June 2026**

Certificate Number: **AC-3489** Certificate Expiry Date: **15 June 2028**

CALIBRATION

Chemical Quantities

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Conductivity Meters [2]	23 µS/cm 447 µS/cm 1 411 µS/cm 2 070 µS/cm	0.88 % of reading + 2.5 µS/cm 0.88 % of reading + 2.5 µS/cm 0.88 % of reading + 2.5 µS/cm 0.88 % of reading + 2.5 µS/cm	Accredited Solutions Locations: S.W.CT W.B.MA
pH Meters [2]	4 pH 7 pH 10 pH	0.03 pH 0.03 pH 0.03 pH	Accredited Solutions Locations: S.W.CT W.B.MA

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source [1]	(1.1 to 3.3) nF (3.3 to 110) nF (110 to 330) nF (0.33 to 1.1) µF (1.1 to 3.3) µF (3.3 to 11) µF	0.5 % of reading + 10 pF 0.25 % of reading + 10 pF 0.25 % of reading + 30 pF 0.25 % of reading + 1 nF 0.25 % of reading + 3 nF 0.25 % of reading + 10 nF	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT W.B.MA
DC Current – Source [1]	(0 to 330) µA (0.33 to 3.3) mA (3.3 to 33) mA (33 to 330) mA 330 mA to 1.1 A (1.1 to 3) A (3 to 11) A	0.15 mA/A + 20 nA 0.1 mA/A + 50 nA 0.1 mA/A + 0.25 µA 0.1 mA/A + 2.5 µA 0.2 mA/A + 40 µA 0.38 mA/A + 40 µA 0.5 mA/A + 0.5 mA	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT W.B.MA
AC Current – Source [1]	(29 to 330) µA 45 Hz to 1 kHz (0.33 to 3.3) mA 45 Hz to 1 kHz (3.3 to 33) mA 45 Hz to 1 kHz (33 to 330) mA 45 Hz to 1 kHz	 1.2 mA/A + 0.1 µA 1 mA/A + 0.15 µA 0.4 mA/A + 2 µA 0.4 mA/A + 20 µA	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT W.B.MA
AC Current – Source [1]	(0.33 to 1.1) A 45 Hz to 1 kHz (1.1 to 3) A 45 Hz to 1 kHz (3 to 11) A 45 Hz to 1 kHz (1 to 5) kHz	 0.5 mA/A + 0.1 mA 0.6 mA/A + 0.1 mA 1 mA/A + 2 mA 30 mA/A + 2 mA	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT W.B.MA
Resistance – Source [1] (Simulation)	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω 110 Ω to 1.1 kΩ (1.1 to 11) kΩ (11 to 110) kΩ 110 kΩ to 1.1 MΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ	40 µΩ/Ω + 1 mΩ 30 µΩ/Ω + 1.5 mΩ 28 µΩ/Ω + 1.4 mΩ 28 µΩ/Ω + 2 mΩ 28 µΩ/Ω + 20 mΩ 28 µΩ/Ω + 0.2 Ω 32 µΩ/Ω + 2 Ω 60 µΩ/Ω + 30 Ω 0.13 mΩ/Ω + 50 Ω	Comparisons performed with a Multifunction Calibrator (This is 1 hr and ± 1 °C since zero-cal) Locations: S.W.CT W.B.MA

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source [1] (Simulation)	(11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ 330 MΩ to 1.1 GΩ	0.25 mΩ/Ω + 2.5 kΩ 0.5 mΩ/Ω + 3 kΩ 3 mΩ/Ω + 0.1 MΩ 15 mΩ/Ω + 0.5 MΩ	Comparisons performed with a Multifunction Calibrator (This is 1 hr and ± 1 °C since zero-cal) Locations: S.W.CT W.B.MA
RTD Resistance – Source [1] (Simulation)	Pt 385, 100 Ω (-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C Pt 3926, 100 Ω (-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C Pt 3916, 100 Ω (-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C Pt 385, 1 000 Ω (-200 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 600) °C (600 to 630) °C	 0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C 0.23 °C 0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C 0.25 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.10 °C 0.23 °C 0.03 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.23 °C	Comparisons performed with Multifunction Calibrator, Electronic Indicator Locations: S.W.CT W.B.MA

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Source [1]	(0 to 330) mV 330 mV to 3.3 V (3.3 to 33) V (33 to 330) V (330 to 1 020) V	20 µV/V + 1 µV 11 µV/V + 2 µV 12 µV/V + 20 µV 18 µV/V + 0.15 mV 18 µV/V + 1.5 mV	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT W.B.MA
AC Voltage – Source [1,2]	(1 to 33) mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (33 to 330) mV (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (0.33 to 3.3) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz (3.3 to 33) V (10 to 45) Hz 45 Hz to 10 kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (33 to 330) V 45 Hz to 1 kHz (1 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	0.8 mV/V + 6 µV 0.15 mV/V + 6 µV 0.2 mV/V + 6 µV 1 mV/V + 6 µV 3.5 mV/V + 12 µV 8 mV/V + 50 µV 0.3 mV/V + 8 µV 0.15 mV/V + 8 µV 0.16 mV/V + 8 µV 0.35 mV/V + 8 µV 0.8 mV/V + 32 µV 2 mV/V + 70 µV 0.3 mV/V + 50 µV 0.15 mV/V + 60 µV 0.19 mV/V + 60 µV 0.3 mV/V + 50 µV 0.7 mV/V + 0.13 mV 2.4 mV/V + 0.6 mV 0.3 mV/V + 0.65 mV 0.15 mV/V + 0.6 mV 0.24 mV/V + 0.6 mV 0.35 mV/V + 0.6 mV 0.9 mV/V + 1.6 mV 0.19 mV/V + 2 mV 0.2 mV/V + 6 mV 0.25 mV/V + 6 mV 0.3 mV/V + 6 mV 2 mV/V + 50 mV	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT

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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source [1,2]	(330 to 1 000) V 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	 3 mV/V + 10 mV 2.5 mV/V + 10 mV 3 mV/V + 10 mV	Comparisons performed with a Multifunction Calibrator Locations: S.W.CT
Electrical Calibration of Thermocouples – Generate & Measure [1]	Type J (-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1 200) °C Type K (-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1 000) °C (1000 to 1 372) °C Type T (-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	 0.27 °C 0.16 °C 0.14 °C 0.17 °C 0.23 °C 0.33 °C 0.18 °C 0.16 °C 0.26 °C 0.4 °C 0.63 °C 0.24 °C 0.16 °C 0.14 °C	Comparisons performed with Multifunction Calibrator Locations: S.W.CT W.B.MA
Hipot Testers	(0.5 to 10) kV	0.1 % of reading + 11 V	Comparisons performed with Electrical Tester Calibrator Locations: S.W.CT
Gauss Meters, Magnetometers	(2 to 100) G	3.4 % of reading + 0.18 G	Magwerks Gauss Meter Calibrator with Coil Locations: S.W.CT

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Calipers [1,2] (OD, ID, Depth, Step)	(0.05 to 80) in	(520 + 3.9*L*) µin	Comparison to Gage Blocks Locations: S.W.CT W.S.MA W.B.MA
Coordinate Measuring Machine [1,2] X-axis	Up to 24 in	(63 + 5.6*L*) µin	Comparisons to Gage Blocks, Step Gage Location: S.W.CT
Cylindrical Plug, Discs [2]	(0.01 to 12) in	(31 + 1.6*L*) µin	Direct measure using P&W Supermicrometer® Locations: S.W.CT W.S.MA W.B.MA
Gage Blocks [2]	(0.01 to 20) in	(6.5 + 1.5*L*) µin	Comparisons to Federal Comparator, Master Gage Blocks Locations: S.W.CT W.S.MA
Height Gage [1,2]	Up to 40 in	(59 + 4.7*L*) µin	Comparison to Gage Blocks Locations: S.W.CT W.B.MA
Horizontal Measuring Machines [1,2]	(1 to 100) in	(28 + 1.6*L*) µin	Comparisons to Renishaw XL-80 Laser Locations: S.W.CT

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Indicators [1] 0.000 01 in Resolution	Up to 2 in	40 µin	Direct measure using Digital Micrometer Locations: S.W.CT W.S.MA W.B.MA
Outside Micrometers [1,2]	(0.05 to 40) in	(48 + 7.9*L*) µin	Comparison to Gage Blocks Locations: S.W.CT W.S.MA W.B.MA
Micrometer Standards [2]	(1 to 36) in	(93 + 8.1*L*) µin	Comparison to Gage Blocks Locations: S.W.CT W.B.MA
Optical Comparators [1,2] Magnification	10X, 20X, 25X, 30X, 31.25X, 50X, 62.5X, 100X, 250X. 500X	450 µin	Comparisons to Size Ball, Check Glass Locations: S.W.CT W.B.MA
Optical Comparators [1,2] Linearity (X-Y axis)	(0.05 to 12) in	(150 + 23*L*) µin	Comparisons to Glass Masters Locations: S.W.CT W.B.MA
Optical Comparators [1,2] Squareness of X to Y axis	3 in	220 µin	Comparisons to Glass Masters Locations: S.W.CT W.B.MA

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Optical Comparators [1,2] Angle	(0 to 90)°	0.01°	Comparisons to Glass Masters Locations: S.W.CT W.B.MA
Pin Gages	(0.01 to 1) in	43 µin	Comparisons to Twin Horizontal Class ZZ Locations: S.W.CT W.B.MA
Profilometers [1]	(1 to 1 000) µin	4 µin	Comparison to Surface Finish Patch Locations: S.W.CT W.S.MA W.B.MA
Profilometer Standards	(1 to 1 000) µin	2 µin	Direct measure using Profilometer SJ-410 Locations: W.S.MA
Ring Gages [2]	(0.04 to 20) in	(17 + 0.7*L*) µin	Comparisons to P&W LabMaster®, Master Gage Blocks, Master Ring Gages Locations: S.W.CT W.S.MA

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Surface Plates [1,2] Overall Flatness Local Flatness (Repeat Readings)	(10 to 120) inDL Up to 200 µin Up to 0.02 in	(66 + 0.6inD) µin 51 µin	In accordance with ASME B89.3.7 using Planekator Repeat-o-Meter <u>Locations:</u> S.W.CT W.B.MA
Thread Measuring Wires [2]	(0.004 8 to 0.289) in	31 µin	Comparisons to P&W Supermicrometer®, Gage Blocks <u>Locations:</u> S.W.CT W.B.MA
Thread Plug Gages [2] Major Diameter Pitch Diameter	(1.6 to 100) mm (1.373 to 96.103) mm	(0.81 + 0.05L) µm (2.4 + 0.03L) µm	Comparisons to P&W Supermicrometer®, Gage Blocks, Thread Wires <u>Locations:</u> S.W.CT W.S.MA W.B.MA
Thread Plug Gages [2] Major Diameter Pitch Diameter	(0.06 to 4) in (0.051 9 to 3.837 6) in	(32 + 1.9L) µin (96 + 1.3L) µin	Comparisons to P&W Supermicrometer®, Gage Blocks, Thread Wires <u>Locations:</u> S.W.CT W.S.MA W.B.MA

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Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Thread Ring Gages [2] Minor Diameter	(1.168 4 to 247.040 4) mm	(1.7 + 0.48*L*) µm	Comparison to Master Plain Class X Plug Gage
Pitch Diameter	(1.305 6 to 249.788 7) mm	(8.6 + 1.6*L*) µm	Master Threaded Set Plug Locations: S.W.CT W.B.MA
Thread Ring Gages [2] Minor Diameter	(0.046 to 9.726) in	(68 + 19*L*) µin	Comparison to Master Plain Class X Plug Gage
Pitch Diameter	(0.051 4 to 9.834 2) in	(340 + 63*L*) µin	Master Threaded Set Plug Locations: S.W.CT W.B.MA
Video Measuring Machine [1,2] Linearity (X-Y axis)	Up to 12 in	(75 + 27*L*) µin	Comparison to Glass Scale
Angle	(0 to 360)°	0.003°	Glass Scale Locations: S.W.CT W.B.MA

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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Analytical Balances [1] (0.000 1 g resolution) (0.001 g resolution)	1 mg to 120 g 10 mg to 620 g	0.57 mg 1.1 mg	ASTM E617 Class 1 weights and internal procedure utilized in the calibration of the weighing system. Locations: S.W.CT W.B.MA
Precision Balances [1] (0.01 g resolution) (0.1 g resolution)	100 mg to 1 200 g 1 g to 10 kg	0.12 g 0.58 g	ASTM E617 Class 1 weights and internal procedure utilized in the calibration of the weighing system. Locations: S.W.CT W.B.MA
Bench Scales [1] (0.001 lb resolution) (0.01 lb resolution)	(0.1 to 10) lb (0.1 to 100) lb	0.001 4 lb 0.008 6 lb	ASTM E617 Class 6 weights and internal procedure utilized in the calibration of the weighing system. Locations: S.W.CT W.B.MA
Floor Scales [1] (0.05 lb resolution) (0.5 lb resolution)	(1 to 500) lb (2.5 to 5 000) lb	0.03 lb 0.29 lb	ASTM E617 Class 6 weights and internal procedure utilized in the calibration of the weighing system. Locations: S.W.CT W.B.MA

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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Force Gages [1]	Up to 200 lbf	0.12 lbf	Comparison to Dead Weight, Hanger Locations: W.S.MA W.B.MA
Force Gages [1]	Up to 1 000 lbf (1 000 to 10 000) lbf (10 000 to 50 000) lbf	0.11 % of reading + 0.041 lbf 0.11 % of reading + 1.3 lbf 0.23 % of reading + 1 lbf	Comparison to Futek Load Cell Locations: W.B.MA
Pipettes [1]	(1 to 1 000) µL	1.2 µL/mL + 14 nL	Gravimetric Method using Analytical Balance. Location: W.B.MA
Rockwell and Rockwell Superficial Testers [1]	HRA < 70 (≥ 70 to < 80) ≥ 80 HRBW < 60 (≥ 60 to < 88) ≥ 88 HRC < 35 (≥ 35 to < 60) ≥ 60 HR15N < 78 (≥ 78 to < 90) ≥ 90 HR15TW < 81 (≥ 81 to < 87) ≥ 87	 1.9 HRA 1.9 HRA 1.9 HRA 1.9 HRBw 1.9 HRBw 1.9 HRBw 1.9 HRC 1.9 HRC 1.9 HRC 1.9 HR15N 1.9 HR15N 1.9 HR15N 1.9 HR15Tw 1.9 HR15Tw 1.9 HR15Tw	Indirect verification per ASTM E18 using Hardness Test Blocks Locations: W.S.MA W.B.MA

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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Rockwell and Rockwell Superficial Testers [1]	HR30N < 55 (≥ 55 to < 77) ≥ 77 HR30TW < 57 (≥ 57 to < 70) ≥ 70 HR45N < 37 (≥ 37 to < 66) ≥ 66 HR45TW < 33 (≥ 33 to < 53) ≥ 53	 1.9 HR30N 1.9 HR30N 1.9 HR30N 1.9 HR30Tw 1.9 HR30Tw 1.9 HR30Tw 1.9 HR45N 1.9 HR45N 1.9 HR45N 1.9 HR45Tw 1.9 HR45Tw 1.9 HR45Tw	Indirect verification per ASTM E18 using Hardness Test Blocks <u>Locations:</u> W.S.MA W.B.MA
Torque Measuring Equipment [1]	(32 to 320) ozf·in	0.94 % of reading	Comparison to Torque Calibrator <u>Locations:</u> S.W.CT W.B.MA
Torque Measuring Equipment [1]	(20 to 60) lbf·in (60 to 200) lbf·in (16 to 500) lbf·ft (500 to 1 400) lbf·ft	0.55 % of reading 0.68 % of reading 0.54 % of reading 1.3 % of reading	Comparison to Torque Calibrator <u>Locations:</u> S.W.CT W.S.MA W.B.MA
Pressure Gages [1]	(-14.5 to 15 000) psi	0.22 % of reading + 0.06 psi	Comparison to Dead Weight Tester, Druck DPI 611 Pressure Calibrator <u>Locations:</u> S.W.CT W.S.MA

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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Mass Determination	0.25 mg to 250 g (250 to 6 000) g (6 to 31) kg	64 mg 25 mg 0.16 g	Comparison to Master Weights using Electronic Balance Location: W.B.MA

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Humidity Measuring Equipment	(10 to 95) %RH	2.2 %RH	Comparison to Accredited Salt Standards Locations: S.W.CT W.B.MA
Infrared Thermometers	(-10 to 150) °C	2.4 °C	Comparison to Omega BB701 Black Body Source (flat plate) $\varepsilon = 0.95$, $\lambda = (8 \text{ to } 14)$ µm Locations: S.W.CT W.B.MA

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DIMENSIONAL MEASUREMENT

2 Dimensional

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Roundness (2D Diameter)	Up to 3 in	7.5 µin	In accordance with ASME Y14.5 using the Roundness Tester. Location: S.W.CT

3 Dimensional

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
3D Dimensional Measurements [2]	X = Up to 31 in Y = Up to 39 in Z = Up to 26 in	(120 + 15*L*) µin	In accordance with ASME Y14.5 using a Coordinate Measuring Machine. Location: S.W.CT

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (k=2), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. The measurand value listed in the Range column is an approximate value. The certified value will be utilized at the time of calibration with the associated measurement uncertainty.
3. L = length in inches or millimeters; D = diameter in inches; inDL = diagonal length in inches.
4. The capabilities of all sites are identical using the same procedures and equipment, under the same environmental conditions.
5. Unless otherwise specified, the laboratory has utilized a calibration procedure that was written and validated internally.

Jason Stine, Vice President

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